Application/Control No.	Applicant(s)/Patent under Reexamination
09/467,611	MIAO ET AL.
Examiner	Art Unit
Jason M. Perilla	2611

SEARCHED				
Class	Subclass	Date	Examiner	
375	295	11/6/2006	JP .	
	316	11/6/2006	JP	
	346	11/6/2006	JP	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East USPAT/USPGPUB	11/6/2006	JP		
Inventor Name Search EAST/EDAN	11/6/2006	JP		
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